Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,719	OGAWA, HIDEHIKO	
Examiner	Art Unit	_
Thomas D. Lee	2625	

SEARCHED				
Class	Subclass	Date	Examiner	
358	1.15, 402, 440	9/27/2005	TDL	
379	100.01	9/27/2005	TDL	
379	100.08	9/27/2005	TDL	
379	100.13	9/27/2005	TDL	
379	100.17	9/27/2005	TDL	
updated		2/2/2006	TDL	
updated		7/20/2006	TDL	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
			1		
Interference Search Printout		7/20/2006	TDL		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		